

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/773,610	YAMANAKA ET AL.	
Examiner		Art Unit		Page 1 of 1
Emmanuel Bayard		2611		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0009565	07-2001	Singvall, Jakob	375/233
*	B	US-6,067,655	05-2000	Kovacs et al.	714/762
*	C	US-2005/0201456	09-2005	Lakkis, Ismail	375/232
*	D	US-6,012,161	01-2000	Ariyavitsakul et al.	714/795
*	E	US-2004/0125884	07-2004	Wei et al.	375/265
*	F	US-6,690,739	02-2004	Mui, Shou Yee	375/265
*	G	US-2003/0123586	07-2003	Yen, Kuang-Yu	375/350
*	H	US-6,850,493	02-2005	Ojard et al.	370/252
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.